

# Back-Illuminated Non-Isolated Single-Photon Avalanche Diode in Foundry CMOS Technology

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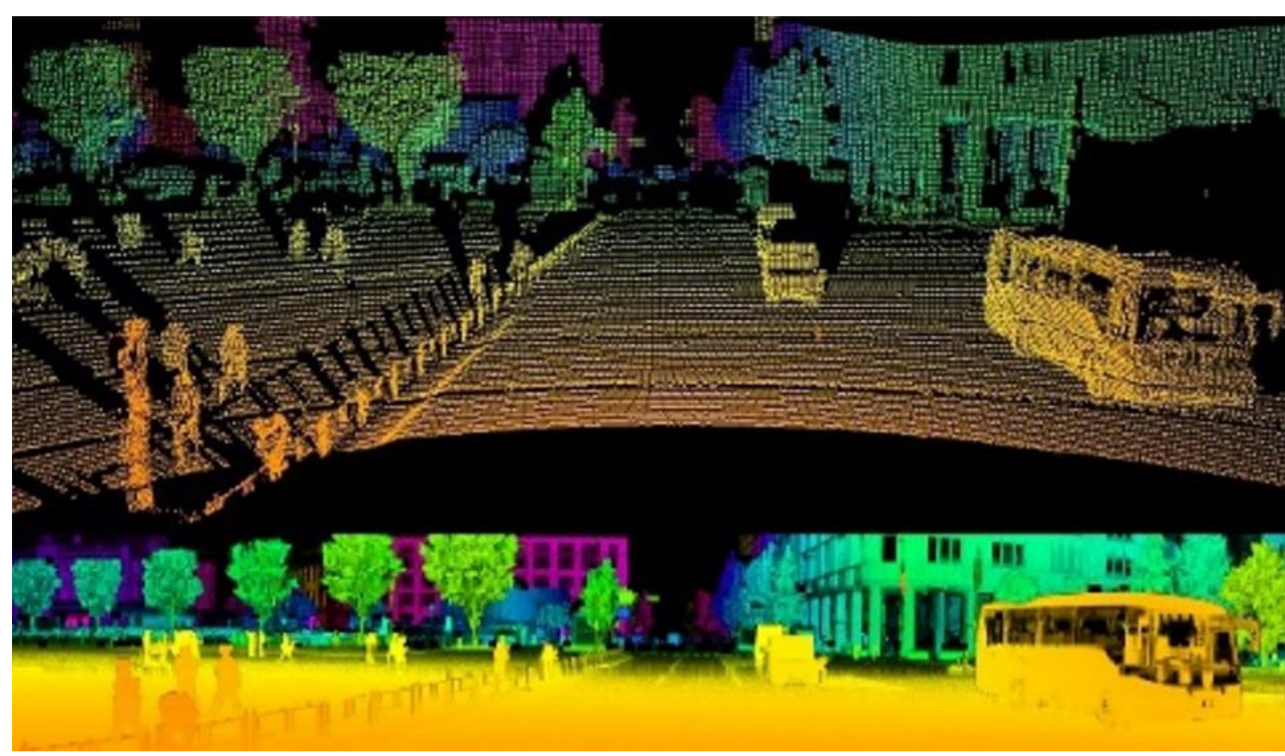
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## SPAD Applications



Source : Sony



Source : GE HealthCare

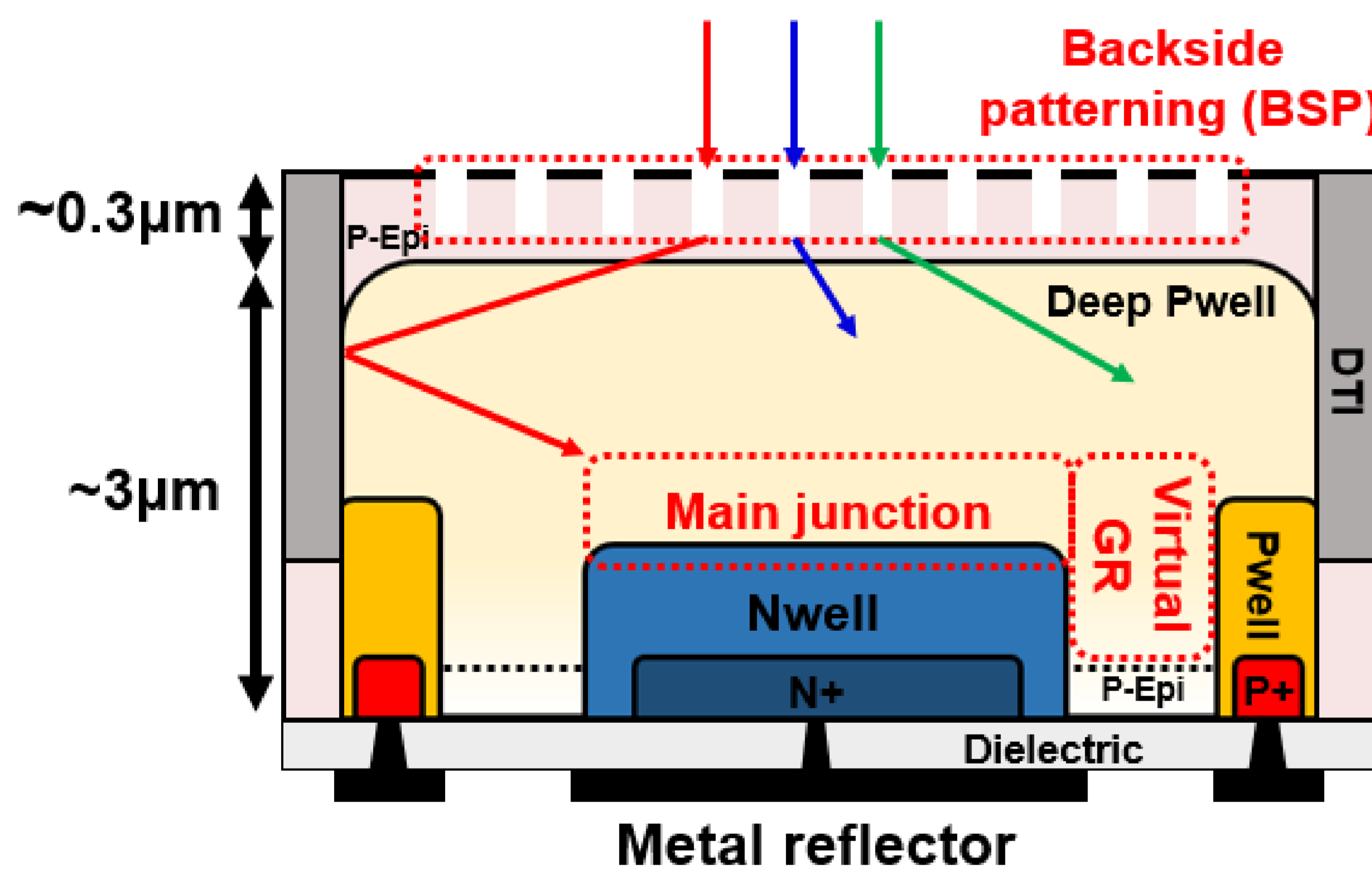
[Autonomous vehicles]

[ToF PET]

- Single-photon avalanche diodes (SPADs) are widely used in several applications such as autonomous vehicles and time-of-flight positron emission tomography (ToF PET).

## Device Structure and Simulation

### [Back-illuminated (BI) non-isolated SPAD]



#### • Device features

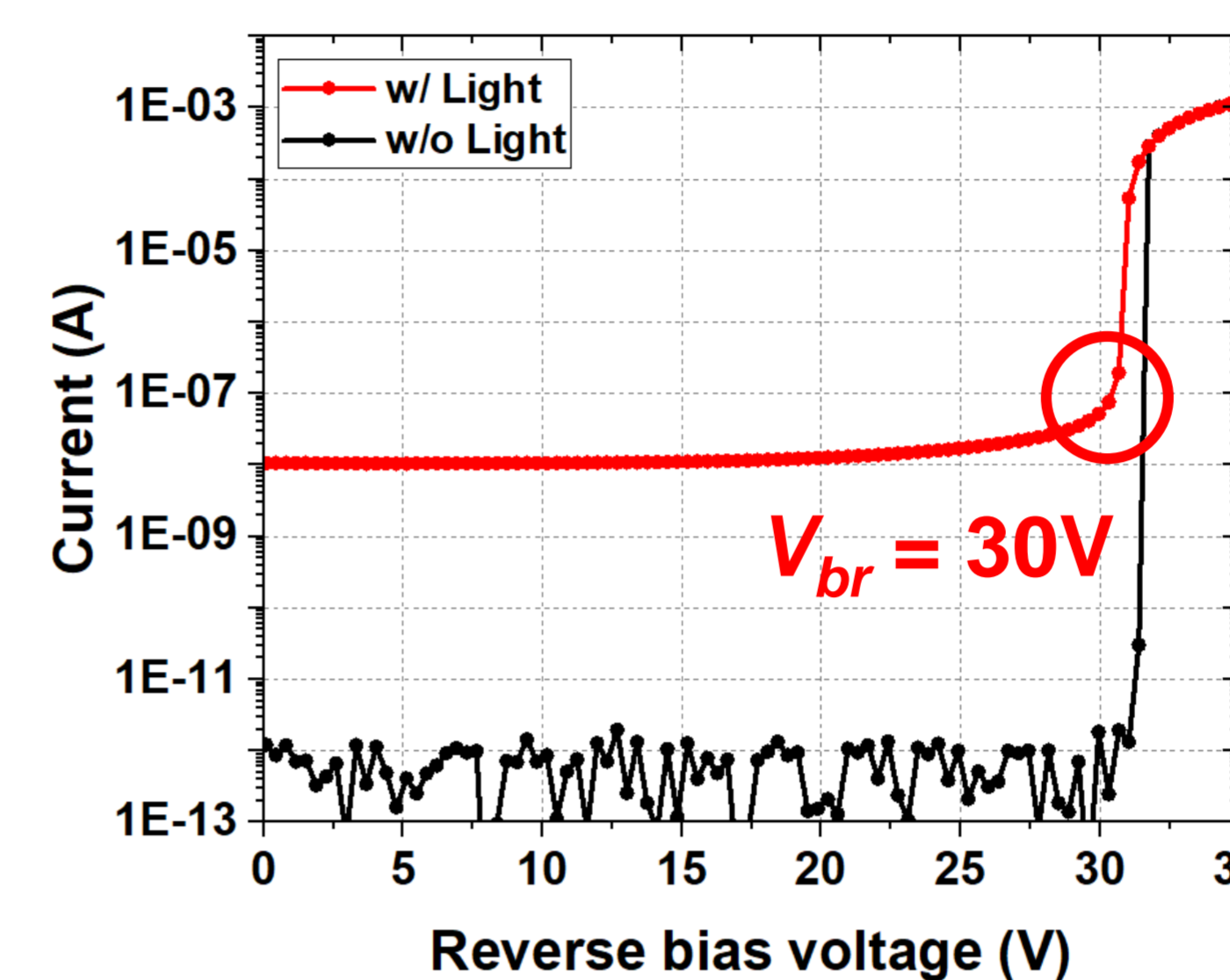
- Main junction : Nwell / Deep Pwell
- Guard-ring : Virtual GR
- Backside patterning (BSP)
- Deep trench isolation (DTI)
- Metal reflector

## Conclusion

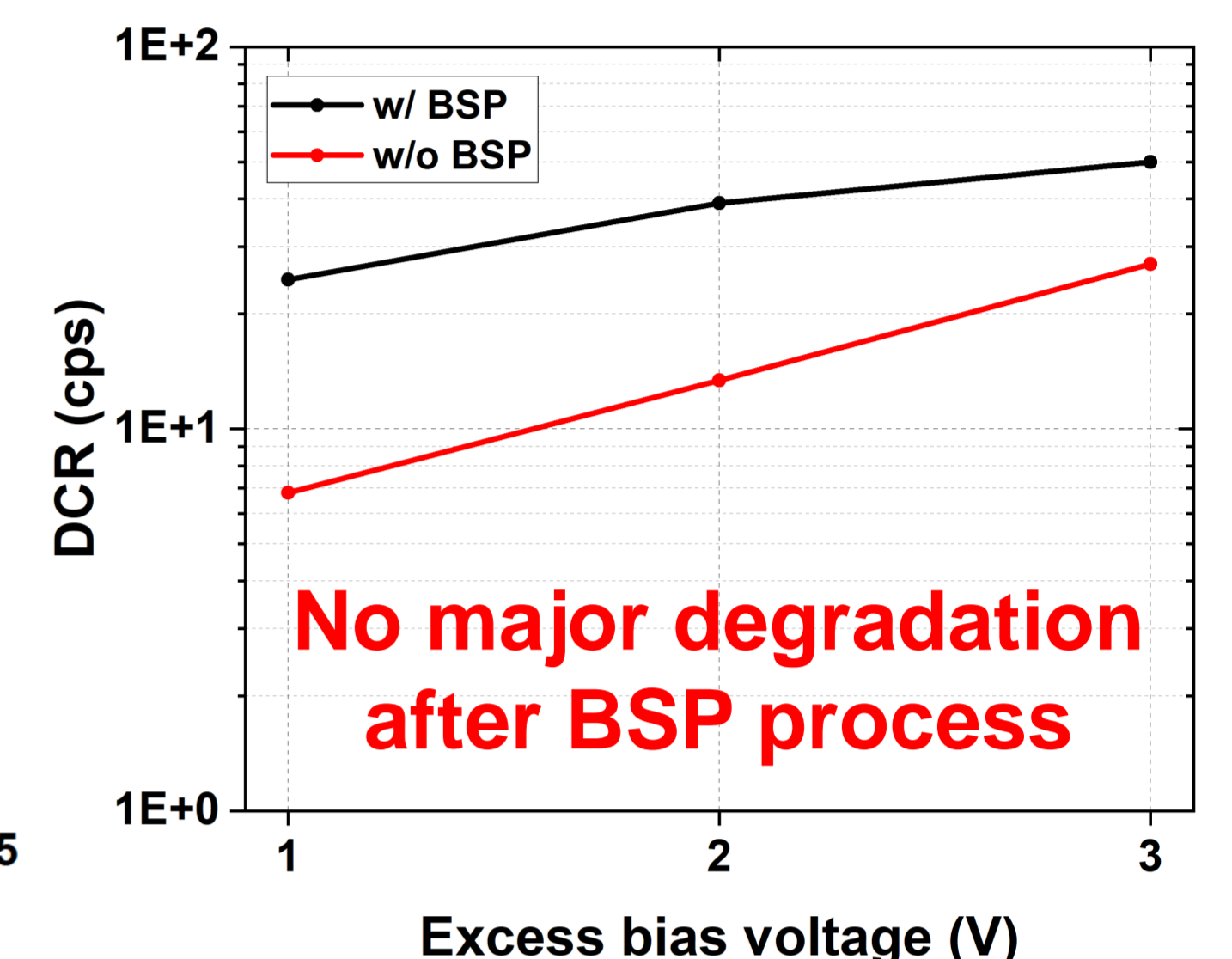
- The proposed BI non-isolated SPAD with backside patterning achieves a ~50% higher PDP at 940nm than the default SPAD while it shows a comparable DCR.
- The PDP will be improved by increasing the thickness of the P-Epi.
- It is expected to play an important role in biomedical and LiDAR applications.

## Results

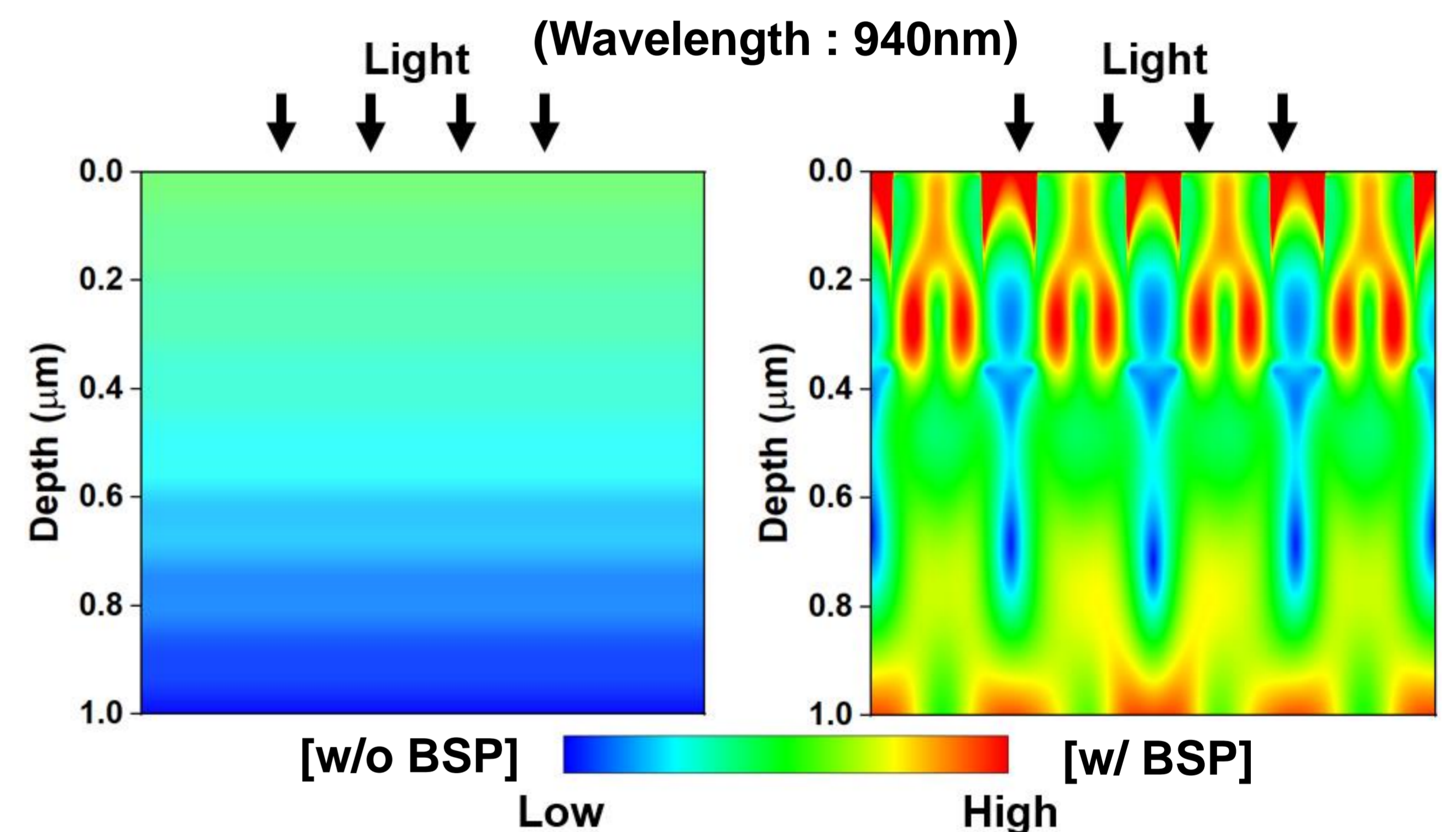
### • I-V characteristics



### • Dark count rate (DCR) comparison

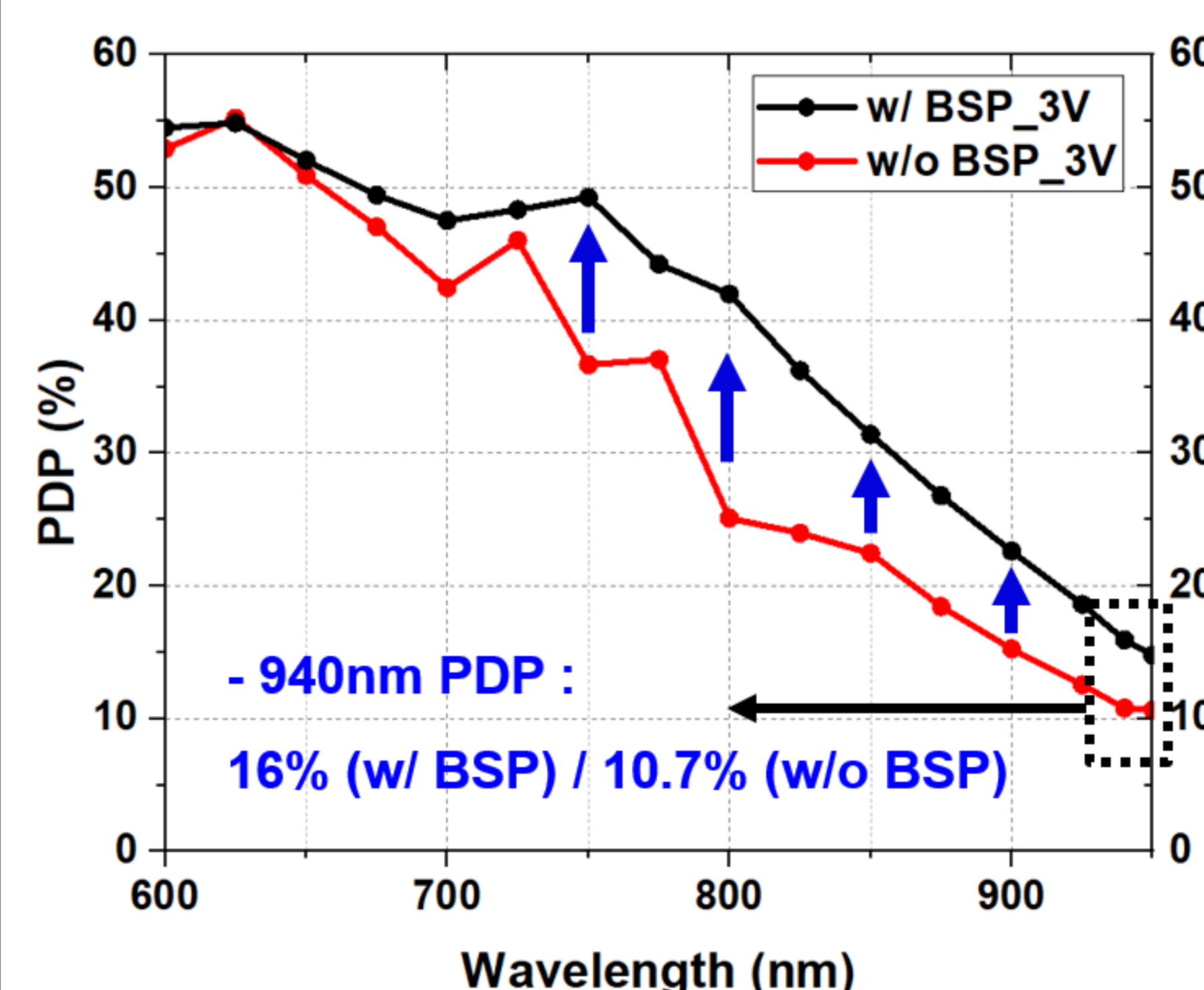


### • Finite-difference time-domain (FDTD) simulation



- Backside patterning (BSP) effectively enhanced the incident light through diffraction.

### • Photon detection probability (PDP) comparison



- Thanks to BSP, the PDP improved at long-wavelengths.

### • Performance summary

	w/o BSP	w/ BSP
Active area	10μm	
Breakdown voltage	30V	
Excess voltage	3V	
DCR (cps / μm <sup>2</sup> )	0.34	0.64
940nm PDP	10.7%	16%